| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|----------|------|--|---|---------------------|---------|------------------|
| L1 | 8853 | (semiconductor or integrated adj circuit) and (burn\$4-in or burn\$4 adj in) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/10/14 14:06 |
| L2 | 213 | 1 and dc near current\$1 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/10/14 14:07 |
| L3 | 167 | 2 and temperature\$1 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/10/14 14:07 |
| L4 | 84 | 3 and frequenc\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/10/14 14:08 |
| L5 | 15 | 4 and ac near current\$1 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/10/14 14:09 |